

EddyCus® TF map 2525SR – Sheet Resistance Imaging Device

P_T_2525SR_22



Highlights

- ▶ Contact-free imaging
- ▶ High resolution imaging (25 to 1,000,000 points)
- ▶ Defect imaging
- ▶ Mapping of encapsulated layers

Device Series

- ▶ Metal thickness (nm, μm)
- ▶ Sheet resistance (Ohm/sq)
- ▶ Emissivity
- ▶ Conductivity / resistivity (mOhm cm)
- ▶ Electrical anisotropy (%)
- ▶ Weight (g/m^2) and drying status (%)
- ▶ Permeability (H/m) *Beta*

SURAGUS GmbH
Maria-Reiche-Strasse 1
01109 Dresden
Germany

上海昊量光电设备有限公司

中国区代理


官网: www.auniontech.com 电话: 021-34241961
邮箱: info@ahuniontech.com
地址: 上海市徐汇区虹梅路2007号远中产业园三期6号楼3楼

Applications

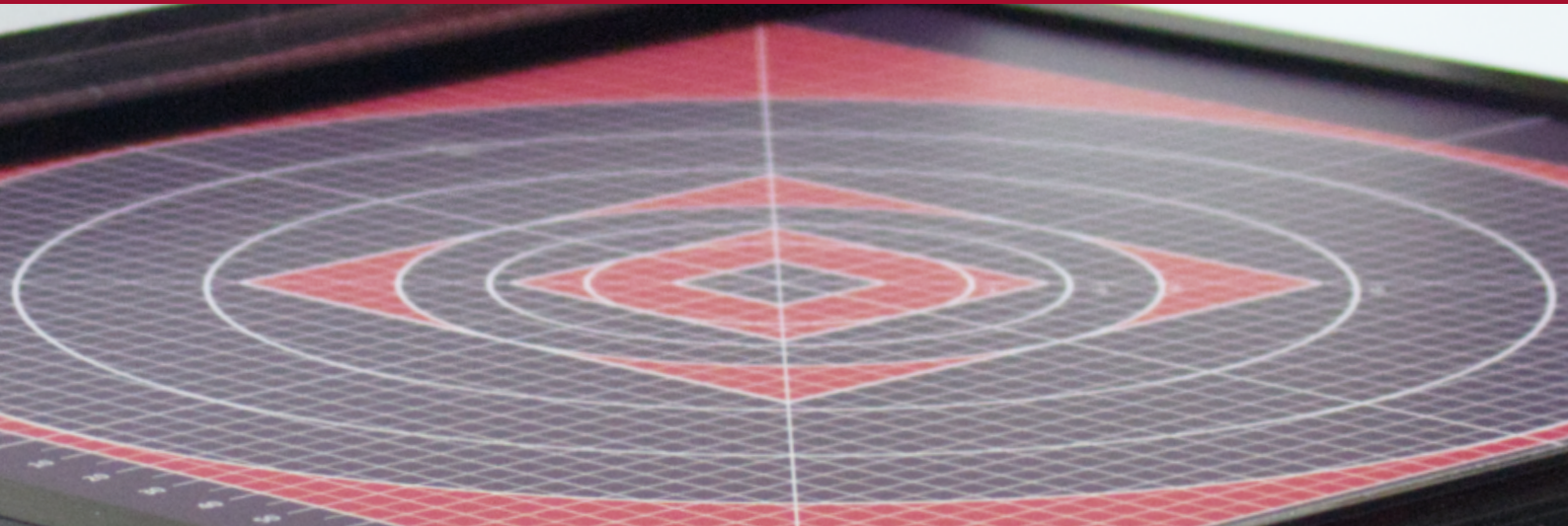
- ▶ Architectural glass (LowE)
- ▶ Touch screens and flat monitors
- ▶ OLED and LED applications
- ▶ Smart-glass applications
- ▶ Transparent antistatic foils
- ▶ Photovoltaics
- ▶ Semiconductors
- ▶ De-icing and heating applications
- ▶ Batteries and fuel cells
- ▶ Packaging materials

Materials

- ▶ Metal films and meshes
- ▶ Conductive oxides
- ▶ Nanowire films
- ▶ Graphene, CNT, Graphite
- ▶ Printed films
- ▶ Conductive polymers (PEDOT:PSS)
- ▶ Other conductive films and materials

Engineered and Made in Germany 





Measurement technology	Non-contact eddy current sensor
Substrates	Foils, glass, wafer, etc.
Max. scanning area	10 inch / 254 mm x 254 mm (larger upon request)
Edge effect correction / exclusion	2 – 10 mm (depending on size, range, setup and requirements)
Max. sample thickness / sensor gap	3 / 5 / 10 / 15 mm (defined by the thickest sample)
Thickness measurement of metal films (e.g. aluminum, copper)	2 nm – 2 mm (in accordance with sheet resistance)
Scanning pitch	1 / 2 / 5 / 10 mm (other upon request)
Measurement points per time (square shaped samples)	100 measurement points in 0.5 minutes 10,000 measurement points in 3 minutes
Scanning time	4 inch / 100 mm x 100 mm in 0.5 to 3 minutes (1 – 10mm pitch) 8 inch / 200 mm x 200 mm in 1.5 to 15 minutes (1 – 10mm pitch)
Device dimensions (w/h/d) / weight	23.6" x 9.05" x 31.5" / 549 mm x 236 mm x 786(836) mm / 27 kg

	VLSR	LSR	MSR
	6 decades are measurable by one sensor, but with slightly affected accuracy		
Range [Ohm/sq]	0.0001 – 0.1	0.01 – 10	0.1 – 100
Accuracy / Bias	± 1%	± 1 – 2%	± 1 – 3%
Repeatability (2σ)	< 0.5%		< 1%

VLSR – Very Low Sheet Resistance , LSR – Low Sheet Resistance , MSR – Medium Sheet Resistance

Device Control and Software

- ▶ Pre-defined measurement and product recipes (sizes, pitches, thresholds)
- ▶ Line scan, histogram and area analysis
- ▶ Black and colored image coding
- ▶ Csv & pdf export
- ▶ SPC summary and export
- ▶ 3 user levels
- ▶ Material database for parameter conversion
- ▶ Edge effect compensation
- ▶ Storage and import of data
- ▶ Export of data sets (e.g. to EddyEva, MS Excel, Origin)

